

TfN/2811

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of

Masanobu ANDO, et al.



Serial No.: 10/564,416

Group Art Unit: 2811

Filing Date: January 12, 2006

Examiner: Sara W. Crane

For: LIGHT EMITTING SEMICONDUCTOR DEVICE AND A METHOD OF  
MANUFACTURING IT

Honorable Commissioner for Patents  
Alexandria, VA 22313-1450

**Submission of European Office Action**

Sir:

Applicants submit the European Search Report dated June 2, 2006, in a counterpart foreign application and listed on the attached form PTO-1449, to the attention of the Examiner in charge of the above-identified application. The European Office Action refers to references previously made of record in the present case.

Please charge any deficiencies in fees and credit any overpayment of fees to Attorney's Deposit Account No. 50-0481.

Respectfully submitted,

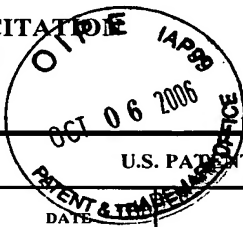
Date: 10/6/06

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Registration No.: 34,386

**INFORMATION DISCLOSURE CITATION**  
(Use several sheets if necessary)



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|---|---|
| Docket Number (Optional)<br><b>F05-420-US</b> | Application Number<br><b>10/564,416</b> |
| Applicant(s)<br><b>Masanobu ANDO, et al.</b>  |   |
| Filing Date<br><b>January 12, 2006</b>        | Group Art Unit<br><b>2811</b>           |

**U.S. PATENT DOCUMENTS**

| *EXAMINER<br>INITIAL | REF | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE<br>IF APPROPRIATE |
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**U.S. PATENT APPLICATION PUBLICATIONS**

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**FOREIGN PATENT DOCUMENTS**

| REF | DOCUMENT NUMBER         | DATE                  | COUNTRY           | CLASS  | SUBCLASS | Translation |    |
|-----|-------------------------|-----------------------|-------------------|--|----------|-------------|----|
|     |                         |                       |                   |  |          | YES         | NO |
|     | <del>EP-0-662 739</del> | <del>07/12/1995</del> | <del>Europe</del> | <del>Previously submitted with IDS dated 4/12/06</del> |          |             |    |
|     | <del>11-026812</del>    | <del>01/29/1999</del> | <del>Japan</del>  | <del>Previously submitted with IDS dated 4/12/06</del> |          |             |    |
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**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

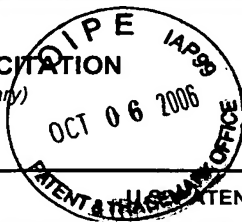
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|  | European Search Report dated June 2, 2006   |
|  | <del>Kneissl, Michael, et al., "Continuous-wave ultraviolet InGaN/InAlGaN multiple-quantum-well laser diodes", Applied Physic Letters, AIP, American Institute of Physics, Melville, NY, US, Vol. 82, No. 15, April 14, 2003, Pages 2386-2388, 012033738</del><br>Previously submitted with IDS dated 4/12/06 |

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# INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)



ATTY DOCKET NO.

F05-420-US

APPLICATION NO.

10/564,416

APPLICANT(S)

Masanobu ANDO, et al.

FILING DATE

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GROUP ART UNIT

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## FOREIGN PATENT DOCUMENTS

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## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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|--|--|--|
|  |  | <del>Nakamura, et al., "InGaN/GaN/AlGaIn-based laser diodes with modulation-doped strained-layer superlattices grown on an epitaxially laterally overgrown GaN substrate", Applied Physics Letter, AIP, American Institute of Physics, Melville, NY, US, Vol. 72, No. 2, January 12, 1998</del><br>previously submitted with IDS dated 4/12/08 |
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EXAMINER

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